

LIST OF INFORMATION DISCLOSED BY APPLICANT

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ATTY. DOCKET NO.
12610-0190SERIAL NO.
08/588,484FILING DATE
January 18, 1996

O P P E

SEP 03 1999

APPLICANT(s)

Thomas G. Thundat, et al.GROUP
2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>RH</i>	AA 3,415,712	12/10/68	R. E. Barker, Jr.			10/31/63
	AB 4,236,893	12/02/80	Rice			04/09/79
	AC 4,242,096	12/30/80	Oliveira <i>et al.</i>			11/14/77
	AD 4,427,881	01/24/84	Ruell			03/09/81
	AE 4,596,697	06/24/86	Ballato			09/04/84
	AF 4,637,987	01/20/87	Minten <i>et al.</i>			05/07/84
	AG 4,735,906	04/05/88	Bastiaans			11/28/84
	AH 4,762,426	08/09/88	Foss			12/19/86
	AI 4,847,193	07/11/89	Richards, <i>et al.</i>			06/18/87
	AJ 4,905,701	03/06/90	Cornelius			06/15/88
<i>RH</i>	AK 4,906,840	03/06/90	Zdeblick <i>et al.</i>	↓	↓/	01/27/88

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	TRANSLATION YES NO.
AL					
AM					
AN					
AO					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>RH</i>	AP	"Microfabrication of Cantilever Styli for the Atomic Force Microscope" by T.R. Albrecht, S. Akamine, T.E. Carver and C. F. Quate, Journal of Vacuum Science & Technology A, Vol. 8, No. 4, Jul./Aug. 1990, pp. 3386-3396.
	AR	"A Mechanical Nanosensor in the Gigahertz Range: Where Mechanics Meets Electronics", by Vu Thien Binh, N. Garcia, A. L. Levanuyk, Surface Sciences, Vol. 301, Nos. 1-3, Jan. 10, 1994, pp. 1,224-1,228.
	AS	"A Nondestructive Method for Determining the Spring Constant of Cantilevers for Scanning Force Microscopy" by J. P. Cleveland and S. Manne, D. Bocek, P. K. Hansma, Review of Scientific Instruments, Vol. 64, No. 2, Feb. 1993, pp. 403-405.
<i>RH</i>	AT	"Adhesion Forces Between Individual Ligand-Receptor Pairs" by Ernst-Ludwig Florin, Vincent T. Moy, Hermann E. Gaub, Science, Vol. 264, 15 April 1994, pp. 415-417.

EXAMINER

R. Henry

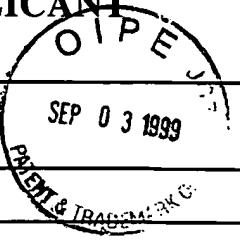
DATE CONSIDERED

1/16/99

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>RH</i>	AU	4,999,284	03/12/91	Ward <i>et al.</i>	T	T	04/06/88
	AV	5,001,053	03/19/91	Takahashi <i>et al.</i>			09/12/88
	AW	5,130,257	07/14/92	Baer <i>et al.</i>			09/29/88
	AX	5,135,852	08/04/92	Ebersole <i>et al.</i>			07/25/89
	AY	5,156,972	10/20/92	Issachar			09/05/90
	AZ	5,221,415	06/22/93	Albrecht <i>et al.</i>			11/26/90
	BA	5,283,087	02/01/94	Baer <i>et al.</i>			11/15/91
	BB	5,306,644	04/26/94	Myerholtz <i>et al.</i>			04/01/93
	BC	5,323,636	06/28/94	McGowan <i>et al.</i>			06/11/93
	BD	5,179,028	01/12/93	Vali <i>et al.</i>			04/20/90
<i>RH</i>	BE	5,339,675	08/23/94	DiLeo <i>et al.</i>			10/08/92
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	TRANSLATION YES NO	
	BF						
	BG						
	BH						
	BI						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>RH</i>	BJ		"Measuring Intermolecular Binding Forces with the Atomic-Force Microscope: The Magnetic Jump Method" by Jan H. Hoh, Paul E. Hillner and Paul K. Hansma, Fifty-Second Annual Meeting Microscopy Society of America, Twenty-Ninth Annual Meeting Microbeam Analysis Society, 31 July-5 August 1994, pp 1054-1055				
<i>RH</i>	BK		"Quantized Adhesion Detected with the Atomic Force Microscope" by Jan H. Hoh, Jason P. Cleveland, Craig B. Prater, Jean-Paul Revel and Paul K. Hansma, Journal of the American Chemical Society, Vol. 114, No. 12, June 3, 1992, pp 4917-4918.				
<i>RH</i>	BL		"Sensing Discrete Streptavidin-Biotin Interactions with Atomic Force Microscopy" by Gil U. Lee, David A. Kidwell, and Richard J. Colton, Langmuir, Vol. 10, No. 2, Feb. 1994, pp. 354-357.				
	BM						
EXAMINER <i>R. Haney</i>				DATE CONSIDERED <i>11/16/96</i>			
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GROUP

2876

SEP 03 1999

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>PH</i>	BN	5,363,697	11/15/94	Nakagawa			04/29/92
	BO	5,372,930	12/13/94	Colton et al.			09/16/92
	BP	5,411,709	05/02/95	Furuki et al.			03/24/92
	BR	5,445,970	08/29/95	Rohr			12/01/94
	BS	5,445,971	08/29/95	Rohr			12/01/94
	BT	5,477,716	12/26/95	Snow			07/27/94
	BU	5,482,678	01/09/96	Sittler.			11/10/94
	BV	5,494,639	02/27/96	Grzegorzewski.			10/13/94
	BW	5,501,986	03/26/96	Ward et al.			07/28/94
	BX	5,550,516	08/27/96	Burns et al.			12/16/94
<i>PH</i>	BY	5,552,274	09/03/96	Oyama et al.			09/07/93

FOREIGN PATENT DOCUMENTS

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	BZ					
	CA					
	CB					
	CC					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

CD		
CE		
CF		
CG		

EXAMINER

R. Henry

DATE CONSIDERED

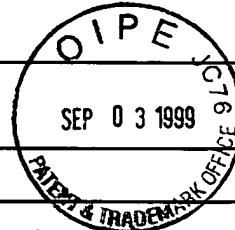
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<i>AH</i>	CH 5,595,908	01/21/97	Fawcett <i>et al.</i>			08/11/89
	CI 5,620,854	04/15/97	Holzrichter <i>et al.</i>			03/13/95
	CJ 5,658,732	08/19/97	Ebersole <i>et al.</i>			03/01/95
	CK 5,705,399	01/06/98	Larue			05/20/94
	CL 5,719,324	02/17/98	Thundat <i>et al.</i>			06/16/95
	CM 5,763,768	06/09/98	Henderson <i>et al.</i>			03/17/97
	CN 5,844,238	12/01/98	Sauer <i>et al.</i>			03/27/96
	CO 5,866,328	02/02/99	Bensimon <i>et al.</i>			04/06/94
<i>AH</i>	CP Re. 35,544	07/01/97	Snow			07/27/94
CR						
CS						

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	DOCUMENT NUMBER	DATE	COUNTRY	NAME	TRANSLATION YES NO.
CT					
CU					
CW					
CX					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

CY		
CZ		
DA		
DB		

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